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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 10559-881001	Application No. 10/681,031	
Information Disclosure Statement by Applicant (Use several sheets If necessary)		Applicant . Yan Borodovsky		
		Filing Date October 7, 2003	Group Art Unit	

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DCD	AQ	"Gratings of regular arrays and trim exposures for ultralarge scale integrated circuit phase shift lithography"; Fritze et al.; Journal Vacuum. Sci Technology B; Vol. 19, No. 6, pp. 1366-::370; Nov/Dec 2001				
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Attorney's Docket No. 10559-881001

Application No. 10/681,031

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Applicant Yan Borodovsky

Filing Date

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Applicant Yan Borodovsky

Group Art Unit . 1756

(37 CFR §1.98(b))

Filing Date October 7, 2003

U.S. Patent Documents Examiner Publication Filing Date Desig. Document Initial ID Number **Patentee** Class If Appropriate Date **Subclass** DCD 6,553,562 April 22, 2003 Capodieci, et al. AA AB AC AD ΑE \mathbf{AF} AG AΗ ΑI ΑJ ΑK

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Substitute Form PTO-1449	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 10559-881001	Application No. 10/681,031	
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